

**CLAIMS**

1. A method for circuit recovery from overstress conditions, comprising the steps of:

(A) detecting an event; and

(B) resetting a device when said event is a first predetermined type and providing recovery when said event is a second predetermined type.

2. The method according to claim 1, wherein step (B) further comprises:

storing said event.

3. The method according to claim 2, wherein step (B) further comprises:

reading an event detector.

4. The method according to claim 3, wherein said event detector comprises a table.

5. The method according to claim 3, wherein step (B) further comprises:

determining an appropriate recovery, wherein said recovery is selected from the group consisting of (i) self  
5 checking, (ii) issuing warnings, (iii) performing back-up operations, and (iv) shutting-down.

6. The method according to claim 5, wherein said recovery further comprises resetting.

7. The method according to claim 1, wherein step (B) further comprises:

performing recovery steps before or in place of a full reset.

8. The method according to claim 1, wherein step (A) further comprises:

determining if resetting or providing recovery is necessary.

9. The method according to claim 1, wherein step (B) further comprises:

storing said event;

reading an event detector; and

5 determining an appropriate recovery.

10. The apparatus according to claim 1, wherein steps  
(A) and (B) are performed by a processor.

11. An apparatus comprising:

means for detecting an event; and

5 means for resetting a device when said event is a first  
predetermined type and providing recovery when said event is a  
second predetermined type.

12. An apparatus comprising:

a detection circuit configured to generate a signal  
having an event condition; and

5 a circuit configured to reset when said event condition  
is a first predetermined type and recover when said event condition  
is a second predetermined type.

13. The apparatus according to claim 12, wherein said  
circuit is further configured to store said event condition.

14. The apparatus according to claim 13, wherein said circuit is further configured to read an event detector to determine a type of said event condition.

15. The apparatus according to claim 14, wherein said circuit is further configured to determine an appropriate recovery.

16. The apparatus according to claim 12, wherein said circuit comprises a microprocessor.

17. The apparatus according to claim 12, wherein said detection circuit comprises an over/under-voltage detection circuit.

18. The apparatus according to claim 12, wherein said detection circuit comprises a high current detection circuit.

19. The apparatus according to claim 12, wherein said detection circuit comprises a noise coupling detection circuit.

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20. The apparatus according to claim 12, wherein said  
detection circuit comprises:

an over/under-voltage detection circuit;

a high current detection circuit; and

a noise coupling detection circuit.

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